ETW'01
IEEE European Test Workshop

Saltsjöbaden, Stockholm, Sweden
May 29 – June 1, 2001

Call for Papers

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The IEEE European Test Workshop is a well-recognized forum for presenting and discussing trends, emerging results, and hot topics in the area of electronic-based circuit and system testing. In 2001, the workshop will take place at Saltsjöbaden, outside Stockholm city center, on one of the most beautiful islands in Sweden.

ETW'01 is sponsored by the IEEE Computer Society - Test Technology Technical Council (TTTC) and organized by Linköping University.

We cordially invite you to participate and submit your contribution to ETW'01, which includes (but is not limited to) the following topics:

Defect-Oriented, Mixed-Signal and Analog Test:
- Failure Analysis, Defect and Fault Modelling
- Yield Analysis
- IDDX Test
- Analog, Mixed-Signal and RF Test
- Thermal Testing
- Signal Integrity Test

System Test:
- Test of Embedded Cores and System-on-Chip
- Test of MCMs and Boards
- Multi-Board System Test
- Micro-System Test
- Manufacturing Test

Design-for-Testability and BIST:
- Scan-based Techniques and Boundary Scan
- High Level DfT
- On-Line and Off-Line BIST
- Test Synthesis and Synthesis for Testability
- Defect/Fault Tolerance and Reliability
- Self-Repair Methodologies

ATPG and Fault Simulation:
- ATPG and High Level TPG
- Fault Simulation
- Debug and Diagnosis
- Test of Memories, Microprocessors, Programmable Logic and MEMs

Submissions: The Program Committee invites original proposals which contain at least 1,000 and at most 5,000 words; full paper submissions are preferred. Electronic submission (using the workshop web page) in Postscript or PDF format is required. Please identify a contact author with his/her complete mailing address, phone number, fax number and e-mail address.

Based on the very positive experience of previous ETWs, the Program Committee solicits also proposals concerning *Industrial Experiences and Challenges*. The deadline for industrial abstract submission is March 9, 2001 (New!).

Proceedings: On site, ETW'01 will deliver handouts of the accepted contributions whose authors wish to provide the corresponding materials. After the workshop, formal proceedings of selected papers will be published by the IEEE Computer Society. The Program Committee will select the contributions to be included in the formal proceedings based on the review results and the quality of the papers included in the handouts. It is also expected that the best contributions will appear in a special issue of the *Journal of Electronic Testing: Theory and Applications* (JETTA), published by Kluwer.

Deadlines and Key Dates: New
- Submission of manuscripts: February 9, 2001
- Submission of abstracts on industrial experiences and challenges: March 9, 2001
- Notification of acceptance: March 23, 2001

IEEE TTTC Test Technology Educational Program (TTEP)

TTEP tutorials will be offered during May, 29 on emerging test technology topics. Tutorial proposals should be submitted according to the guidelines given at http://computer.org/tab/tttc/teg/ttep.

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Please visit the ETW 2001 web page at: **http://www.liu.se/etw01**